Se	arch	Note:	S

Application/Control No.	Applicant(s)/Patent u	ınder
10/663,044	LAVERICK ET AL.	
Examiner	Art Unit	
LUU MATTHEW	3663	

SEARCHED			
Class	Subclass	Date	Examiner
701	200-21	s 12/23/	05 M.L
296	44.3		
	34.34		
	37.1		
	37.8		
	87.12		
	37.13		
ABOVE	UPDATE	>5/406 +	W.L_

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			N.A.

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
babwae taow*	12/20/08	N.L.	
* Consulted with Youel Beautien	15/20/06	H.L.	
* Consulted with Tan Uguyan	12/40/06	N,C	
* Frest searchod	12/23/05	μ.υ.	
* FOST SPARCHED	1/6/06	N.L.	
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